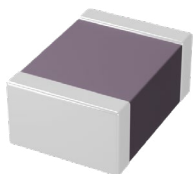


APPLICATIONS

RF and microwave communication (100MHz - 5GHz) for satellite communication, base station, wireless devices, radar



RoHS
compliant

ELECTRICAL PARAMETERS

ELECTRICAL CHARACTERISTICS:
at + 25°C unless otherwise specified

OPERATING TEMPERATURE:
- 55°C, + 125°C

TEMPERATURE COEFFICIENT:
± 30ppm

DISSIPATION FACTOR:
≤ 5.10⁻⁴ at 1Vrms and 1MHz for values ≤ 1000pF
≤ 5.10⁻⁴ at 1Vrms and 1KHz for values > 1000pF

INSULATION RESISTANCE (IR):
25°C/Un 10⁵ MOhm or 1000 Ohm-Farad whichever is less
125°C/Un 10⁴ MOhm or 100 Ohm-Farad whichever is less

DIELECTRIC STRENGTH TEST:
2.5Un U≤200V | U+250V 200<U≤500 | 1.5U 500<U<1000 | 1.2U U≥1000
for 5s with 50mA max charging current

QUICK REFERENCE DATA

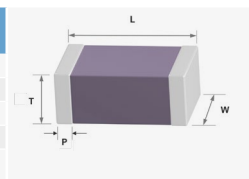
	0402	0504	0603	0709	0805	1206	1210
MIN	0.1pF	0.1pF	0.1pF	0.1pF	0.1pF	0.3pF	0.3pF
50V	68pF	560pF	390pF	1,0nF	1,5nF	4,7nF	8,2nF
100V	47pF	560pF	390pF	1,0nF	1,5nF	4,7nF	8,2nF
200V	27pF	560pF	390pF	1,0nF	1,5nF	3,9nF	7,5nF
500V			100pF	100pF	470pF	1,2nF	3,3nF

ORDERING INFORMATION

1206	Q	560	F	E	X	B	-
SIZE	SIZE	DIELECTRIC	CAPACITANCE	TOLERANCE	VOLTAGE	PACKAGING	SPECIAL
0402 0504 0603 0805 1206 1210	Q = High Q	Expressed in picofarads (pF). The first two digits are significant, the third digit gives the number of noughts. Example : 102 = 1 000pF For special values R is used as decimal separator Example 12R7 = 12.7pF 1340R0 = 1340pF	A = ±0.05pF if < 10pF and 0.05% if > 10pF B = ± 0.1pF C = ± 0,25pF D = ± 0,5pF F = ± 1% G = ± 2% J = ± 5%	A = 50V B = 100V C = 200V P = 250V E = 500V	X = Nickel Tin C = Copper Tin (Non magnetic) F = Silver Palladium (Non magnetic) W = Nickel Gold Flash G = Nickel Gold Thick H = Dipped SnPb I = Electrolytic SnPb	B = Reel V = Bulk	- Dxx = Reliability spec Exx = Sorting spec

DIMENSIONS IN MILLIMETERS

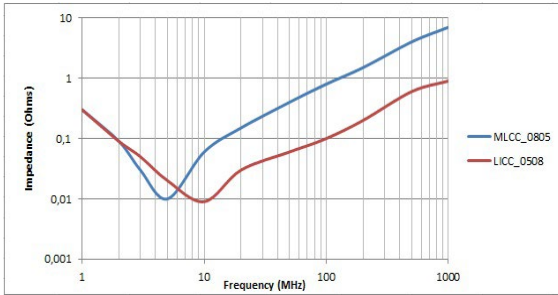
	0402	0603	0709	0805	1206	1210
LENGTH (L)	1.00 ± 0.1	1.60 ± 0.1	1.80 ± 0.2	2.00 ± 0.2	3.20 ± 0.2	3.20 ± 0.2
WIDTH (W)	0.50 ± 0.1	0.80 ± 0.1	2.30 ± 0.2	1.25 ± 0.2	1.60 ± 0.2	2.50 ± 0.2
THICKNESS MAX (T)	0.60	0.90	2.90	1.40	1.70	1.70
TERMINATION (P)	MIN	0.10	0.25	0.25	0.25	0.25
	MAX	0.40	0.40	0.50	0.70	0.70



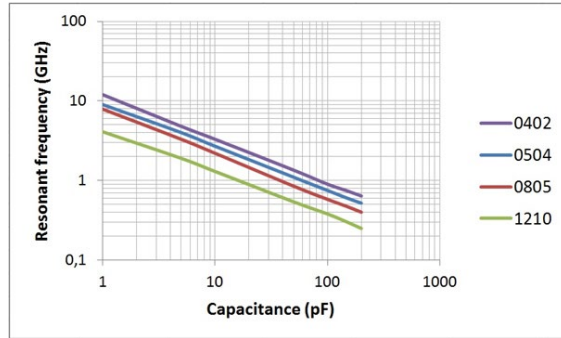


TYPICAL CHARACTERISTICS

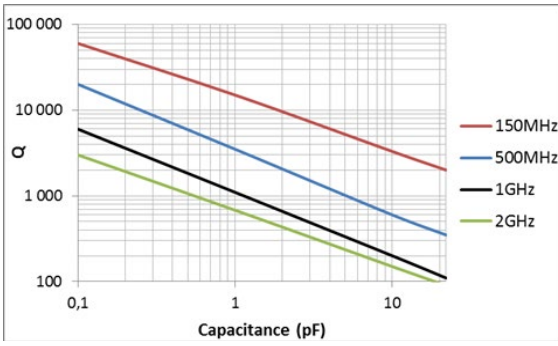
Temperature coefficient of capacitance



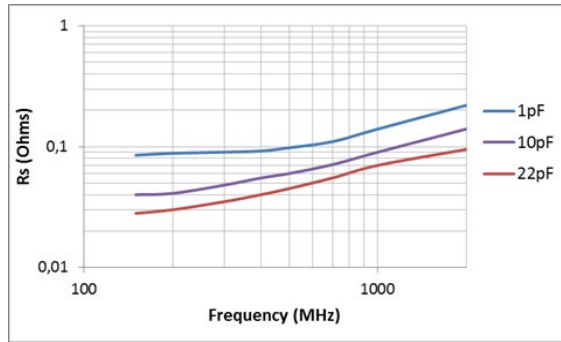
Series resonant frequency



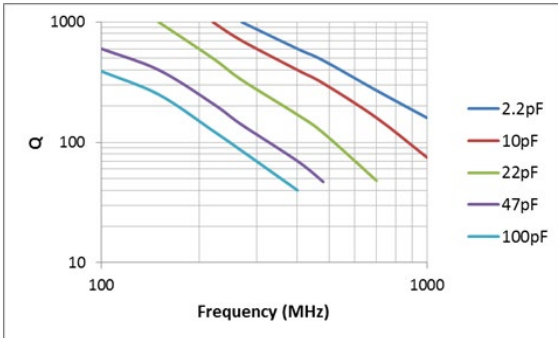
Q / Frequency - 0402, 200V



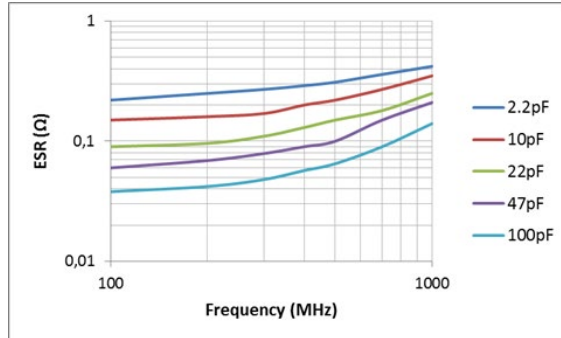
ESR / Frequency - 0402, 200V



Q / Frequency - 0805, 1206, 200V



ESR / Frequency - 0805, 1206, 200V



STORAGE

To prevent the damage of solderability of terminations, the following storage conditions are recommended :

Indoors under 5 ~ 40°C and 20% ~ 70% RH.

No harmful gases containing sulfuric acid, ammonia, hydrogen sulfide or chlorine.

Packaging should not be opened until the capacitors are required for use. If opened, the pack should be re-sealed as soon as possible. Taped products should be stored out of direct sunlight, which might promote deterioration in tape or adhesion performance. The product is recommended to be used within 24 months after shipment. Extended shelf life over this period require a solderability check before use.

HANDLING

Chip capacitors are dense, hard, brittle, and abrasive materials. They are liable to suffer mechanical damage, in the form of cracks or chips. Chip Capacitors should be handled with care to avoid contamination or damage. To use vacuum or plastic tweezers to pick up or plastic tweezers is recommended for manual placement. Tape and reeled packages are suitable for automatic pick and placement machine.

PREHEAT

In order to minimize the risk of thermal shock during soldering, a carefully controlled preheat is required.

The rate of preheat should not exceed 3°C per second.

SOLDERING FLUX

Use mildly activated rosin RA and RMA fluxes, but do not use activated flux. The amount of solder in each solder joint should be controlled to prevent the damage of chip capacitors caused by the stress between solder, chips, and substrate.

SOLDERING TYPE

Lead containing solders, such as Sn60, Sn62 or Sn63 and lead free solders, such as SnAgCu, can all be used with our MLCCs.

In case of non-magnetic termination code C, use lead containing or lead (Pb)-free SAC305 solders.

SOLDERING HEIGHT

The solder climbing minimum height is suggesting to 25% of chip thickness or 500um whichever is less.

(Reference from IPC-610E)

COOLING

After soldering, cool the chips and the substrate gradually to room temperature. Natural cooling in air is recommended to minimize stress in the solder joint.

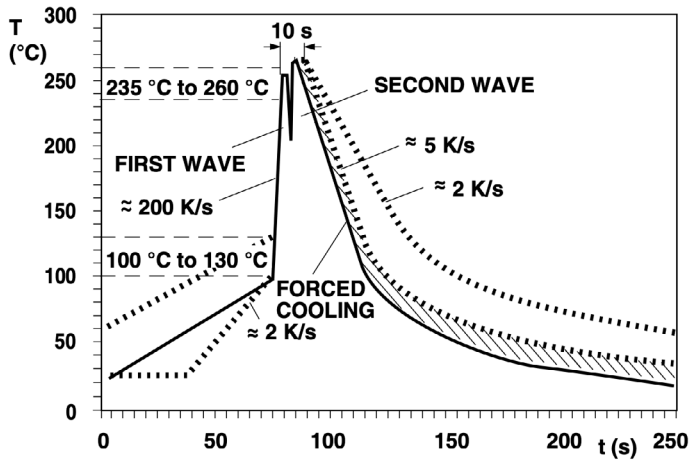
CLEANING

All flux residues must be removed by using suitable electronic-grade vapor-cleaning solvents to eliminate contamination that could cause electrolytic surface corrosion. Good results can be obtained by using ultrasonic cleaning of the solvent. The choice of the proper system is depends upon many factors such as component mix, flux, and solder paste and assembly method. The ability of the cleaning system to remove flux residues and contamination from under the chips is very important.

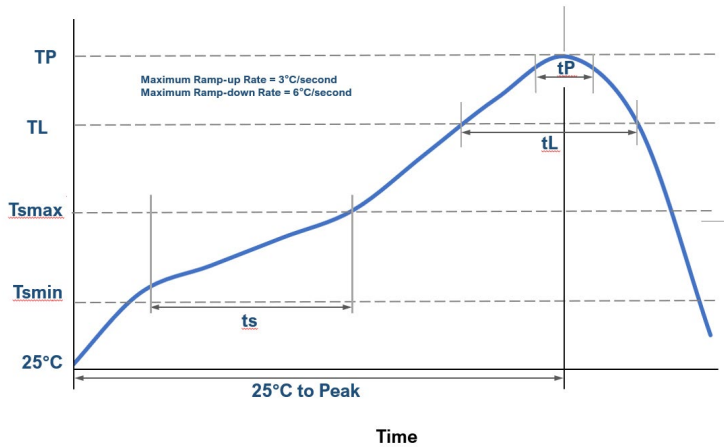
SOLDERING CONDITIONS

SIZE	THICKNESS	WAVE	REFLOW
0402	All	0	0
0505	All	0	0
0603	All	0	0
0805	< 1.25mm	0	0
0805	≥ 1.25mm	0	0
1111	< 1.25mm	0	0
1111	≥ 1.25mm	0	0
1206	< 1.25mm	0	0
1206	≥ 1.25mm	0	0
1210	< 1.25mm	0	0
1210	≥ 1.25mm	0	0
larger than 1210	All	0	0
High compact	All	0	0

WAVE SOLDERING PROFILE

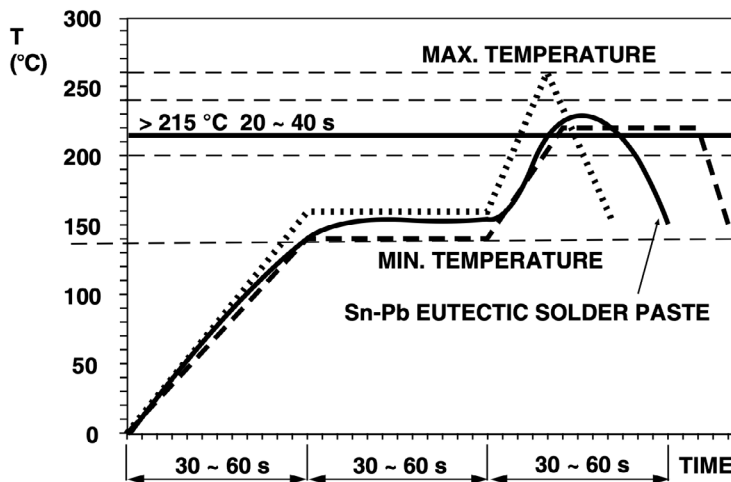


LEADFREE REFLOW SOLDERING PROFILE



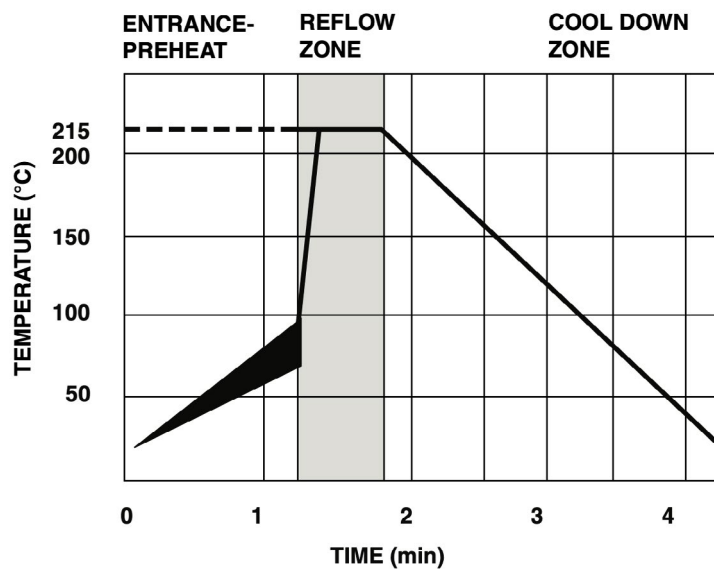
PROFILE FEATURE	LEAD FREE (SAC 305)
Tsmin	150°C
Tsmax	190°C
Time from Tsmin to Tsmax	60 - 120 seconds
Ramp-up Rate	3°C/second max
Liquidous Temperature	217°C
Time above Liquidous	60 - 120 seconds
Peak Temperature	250°C
Time within 5°C of maximum	10 seconds max
Peak Temperature	250°C
Ramp-down Rate	6°C/second max
Time 25°C to Peak	8min max

SNPB REFLOW SOLDERING PROFILE



VAPOUR PHASE REFLOW PROFILE

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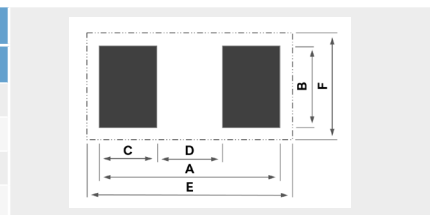
HAND SOLDERING

Hand soldering is not recommended as the thermal shock may cause a crack, however if used the following recommendations should be taken :

- Soldering iron tip diameter ≤ 3.0 mm and wattage max. 20W.
- The Capacitors shall be pre-heated to 150°C and that the temperature gradient between the devices and the tip of the soldering iron.
- Tip temperature ≤ 280 °C and should't be applied for more than 5 seconds.
- The required amount of solder shall be melted on the soldering tip.
- The tip of iron should not contact the ceramic body directly.
- The Capacitors shall be cooled gradually at room temperature after soldering.
- Forced air cooling is not allowed.

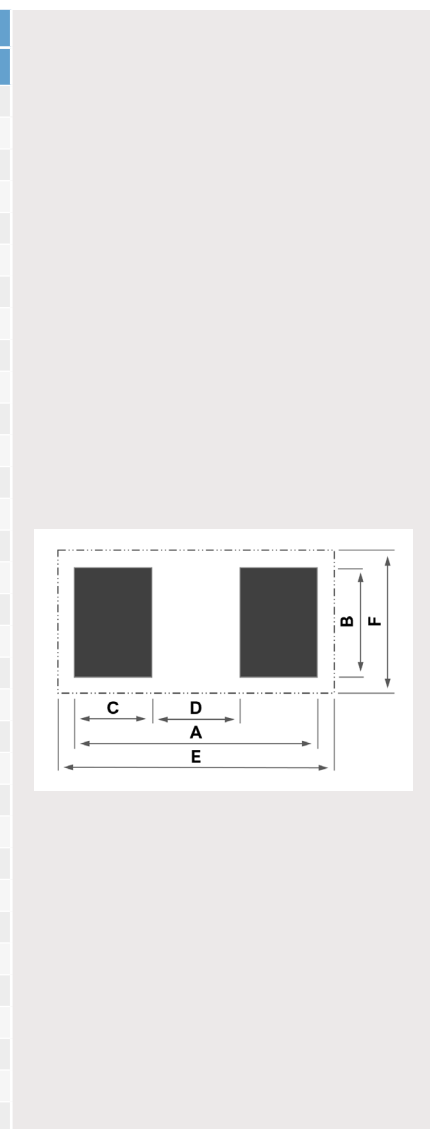
TYPICAL SMD FOOTPRINT WAVE SOLDERING

SIZE	FOOTPRINT DIMENSIONS IN MM					
	A	B	C	D	E	F
0603	2.40	0.80	0.70	1.00	3.10	1.40
0805	3.20	1.30	0.90	1.40	4.10	1.85
1206	4.80	1.70	1.25	2.30	5.90	2.25
1210	4.80	2.60	1.25	2.30	5.90	3.15



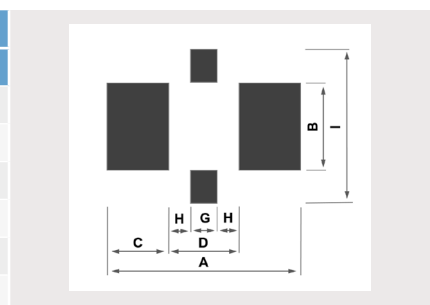
TYPICAL SMD FOOTPRINT REFLOW SOLDERING

SIZE	FOOTPRINT DIMENSIONS IN mm					
	A	B	C	D	E	F
0201	0.65	0.30	0.21	0.23	0.90	0.60
0204	1.00	1.00	0.30	0.40	1.25	1.45
0402	1.50	0.50	0.40	0.70	1.75	0.95
0306	1.30	1.60	0.40	0.50	1.55	2.05
0404	1.50	1.00	0.40	0.70	1.75	1.45
0504	1.90	1.00	0.40	1.10	2.15	1.45
0505	1.90	1.30	0.50	0.80	2.15	1.75
0508	1.90	2.00	0.50	0.90	2.15	2.55
0603	2.30	0.80	0.60	1.10	2.55	1.35
0612	2.30	3.20	0.60	1.10	2.55	3.75
0805	2.90	1.25	0.90	1.10	3.15	1.80
1206	4.10	1.60	0.90	2.30	4.35	2.25
1210	4.10	2.50	1.00	2.10	4.35	3.15
1808	5.50	2.10	1.20	3.10	5.75	2.75
1812	5.50	3.30	1.20	3.10	5.75	3.95
1825	5.50	6.55	1.20	3.10	5.75	7.20
2211	6.80	3.00	1.40	4.00	7.05	3.65
2220	6.80	5.40	1.40	4.00	7.05	6.05
2225	6.80	6.70	1.65	3.50	7.05	7.50
2525	7.70	6.75	1.65	4.40	7.95	7.55
2825	8.40	6.70	1.65	5.10	8.65	7.50
3033	9.00	8.80	1.95	5.10	9.25	9.60
3640	10.55	10.70	2.35	5.85	10.80	11.50
4040	11.60	10.70	2.35	6.90	11.85	11.50
40100	11.60	26.20	2.35	6.90	11.85	27.00
5550	15.50	13.20	2.35	10.80	15.75	14.00
6080	16.70	20.80	2.35	12.00	16.95	21.60
6660	18.30	15.70	2.35	13.60	18.55	16.50
8060	21.90	15.70	2.35	17.20	22.15	16.50
80150	21.90	38.90	2.35	17.20	22.15	39.70
HIGH COMPACT 1210	4.15	2.60	1.15	1.85	5.05	3.30
HIGH COMPACT 1812	5.75	3.40	1.35	3.05	6.70	4.20
HIGH COMPACT 2220	6.80	5.50	1.70	3.40	7.70	6.30



TYPICAL FILTER FOOTPRINT REFLOW SOLDERING

SIZE	FOOTPRINT DIMENSIONS IN mm						
	A	B	C	D	G	H	I
0603	2.30	0.80	0.45	1.40	0.60	0.40	1.50
0805	2.90	1.25	0.90	1.80	0.80	0.50	2.00
1206	4.10	1.60	0.90	2.40	1.00	0.70	3.00
1806	5.50	1.60	1.20	3.20	1.00	1.10	3.00
1812	5.50	3.30	1.20	3.90	1.50	1.20	4.80
2220	6.80	5.40	1.40	4.50	1.50	1.50	7.00





ORDERING INFORMATION

SRMC	0603	Y	102	J	A	-	L	040	-	-	-	B	-
SERIE	SIZE	DIELECTRIC	CAPACITANCE	TOLERANCE	VOLTAGE	TERMINAISON	FORM	HEIGHT	LEADS	COATING	CUR-RENT	PACKAGING	SPECIAL
-	0201	Q = High Q	Expressed in picofarads (pF)	A = ± 0.05pF/0.1%	Y = 4V	- = Sn lead/lead frame	-	020	-	-	-	B = Reel	-
FK	0204	A = NPO		B = ± 0.1pF	R = 6.3V	X = Nickel Tin	J	030	2 to 10	-	1	V = Bulk	BM = BME
FH	0402	P = N2T	The first two digits are significant,	C = ± 0,25pF	Q = 10V	F = Palladium-Silver	L	040	B	I = Conformal-Coating	2	T = Tray Package	Dxx = Reliability spec
SREV	0303	X = BX	the third digit gives the number of noughts	D = ± 0,5pF	J = 16V	P = Polymer Tin (Flex)	D	050		H = EpoxyCoating		W = Waffle Pack	Exx = Sorting spec
MCF	0306	Y=X7R		E = ± 0.5%	X = 25V	C = Copper Tin (Non magnetic)	M	060					H = High Reliability
M2F	0404	BY=2C1	Example : 102 = 1 000pF	F = ± 1%	Z = 35V	CP = Copper Polymer Tin (Non magnetic)	T = 2	070					Q = Anti-Arcing
MPF	0505	T = X7S	For special values R is used as decimal separator	G = ± 2%	A = 50V	W = Nickel Gold Flash	leads	080					E = Anti Bending
SRMC	0508	S = X5R	Example 12R7 = 12.7pF	J = ± 5%	U = 63V	G = Nickel Gold Thick	U = 4	090					Z = Anti-Arcing + Anti-Bending
SRTV	0603	R = X6S	Example 1340R0 = 1340pF	K = ± 10%	B = 100V	HP = Dipped SnPb Polymer	leads	100					
SR	0612	V = Y5V		M = ± 20%	C = 200V	H = Dipped SnPb		110					
SA	0805	U = X8R		Z = -20% +80%	P = 250V	S = Dipped SAC		120					
H	1206				D = 300V	SP = Polymer Dipped SAC		130					
	1210				E = 500V	I = Electrolytic SnPb		140					
	1808				F = 630V	IP = Polymer Electrolytical SnPb		160					
	1812				G = 1000V	Q = Solderable Silver		180					
	1825				O = 1500V	M = Microstrip							
	2211				H = 2000V	A = Axial Ribbon							
	2220				T = 2500V	R = Radial Ribbon							
	2225				I = 3000V	U = Axial Wire							
	2325				K = 4000V	V = Radial Wire							
	2525				L = 5000V	CM = Microstrip (Non magnetic)							
	2825				6 = 6000V	CA = Axial Ribbon (Non magnetic)							
	3033				S = 7200V	CR = Radia Ribbon (Non magnetic)							
	3640				8 = 8000V	CU = Axial Wire (Non magnetic)							
	4040				10 = 10000V	CV = Radial Wire (Non magnetic)							
	40100				12 = 12000V								
	5550				15 = 15000V								
	6080												
	6660												
	7274												
	8060												
	80150												
	40 to 94												

RELIABILITY

OPTIONAL CODE	TESTING DETAIL
D03	Burn-In 100% 125° 168H, no default allowed
D05	Burn-In 100% 125° 168H, less than 5% default allowed VRT CEI 68-2-14 10 cycles 0V -55°C/+125°C, less than 5% default allowed 20 pieces life test 125°C, 1.5Un, 1 default allowed
D20	AECQ-200
D30	Screened and LAT according to ECSS-3009 for space application
D32	Evaluation version for space development according to ECSS-2310
COTS1	Class 1 COTS+ according to ECSS-Q-ST-60-13C-Rev1
COTS2	Class 2 COTS+ according to ECSS-Q-ST-60-13C-Rev1
COTS3	Class 3 COTS+ according to ECSS-Q-ST-60-13C-Rev1

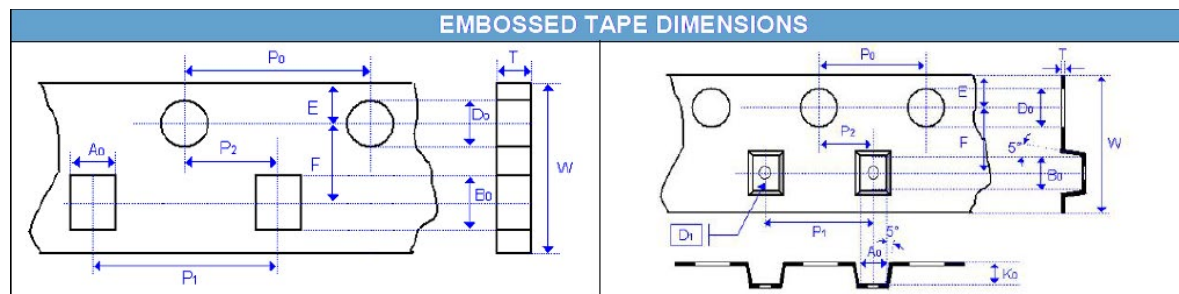
SORTING

OPTIONAL CODE	SORTING DETAIL
E01	2 cells sorting 0 to +2,5 & +2,5 to +5 (% or pF according to value)
E02	4 cells sorting -5 to -2,5 ; -2,5 to 0 ; 0 to +2,5 & +2,5 to 5 (% or pF according to value)
E21	2% cells

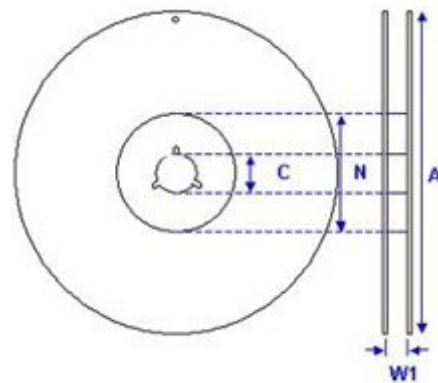


PACKAGE DIMENSION AND QUANTITY

SIZE	THICKNESS	PAPER TAPE		PLASTIC TAPE	
		7 REEL	13 REEL	7' REEL	13 REEL
0402	0.5 ± 0.05	10 K	50 K		
0504	0.6 ± 0.05			4K	15K
	0.9 ± 0.05			4K	15K
0603	0.7 ± 0.07	4K		4K	15K
	0.9 ± 0.07	4K	15K	4K	15K
	0.9 ± 0.07			4K	15K
	1.1 ± 0.07			4K	15K
0805	0.8 ± 0.07	4K	15K	4K	15K
	0.9 ± 0.07			4K	10K
	1.1 ± 0.07			3K	10K
	1.3 ± 0.07			3K	10K
1206	1.1 ± 0.1			3K	10K
	1.4 ± 0.1			3K	8K
	1.8 ± 0.1			2K	8K
1210	1.4 ± 0.1			3K	8K
	1.8 ± 0.1			1K	6K
1808	1.4 ± 0.1			3K	8K
1812	1.6 ± 0.1			2K	8K
	2.1 ± 0.1			1K	6K
	2.8 ± 0.1			1K	6K
2220	1.8 ± 0.1			1K	6K
	3.0 ± 0.1			0.5K	2K
2225	3.0 ± 0.1			0.5K	2K
3033	3.0 ± 0.1			0.5K	2K
3640	3.0 ± 0.1			0.5K	2K
5440	3.9 ± 0.1				0.5K - 1K
HIGH COMPACT 1210				1K	6K
HIGH COMPACT 1812				1K	6K
HIGH COMPACT 2220				0.5K	2K



REEL SIZE	7	7	13
C	13.0 +0.5/-0.2	13.0 +0.5/-0.2	13.0 +0.7/-0.3
W1	8.4 +1.5/-0	12.4 +2.0/-0	8.4 +2.0/-0
A	178.0 ±0.10	178.0 ±0.10	330.0 ±1.0
N	60.0 ±1.0	80.0 ±1.0	100 ±1.0



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RELIABILITY PRINCIPLES OVERVIEW GENERAL PRODUCTION

In order to guarantee highly reliable products to their customers, SRT-Microcéramique follows a strict quality policy which is explained below :

- According to AECQ philosophy, each component belongs to a family, which most restrictive members (four corners) have been fully qualified.
- PME components are produced in our Vendôme facility, with very stable process and equipments, in order to ensure Reliability and reproductibility.
- Reliability is based on batch tests, new product or equipment-specific qualifications and periodic requalifications.
- In addition to those regular tests, our quality departement launches regular accelerated tests to further deepens our reliability datas.
- Tests and qualifications of our standard products are based on AECQ methodology and are qualified according to the following limits.
- In accordance to AECQ methodology, specifics tests and limits can be adapted to fit our clients' needs.
- A whole range of stricter reliability tests can be offered for high Reliability products (burn-in, shocks, pulses...) for medical, space and defense applications.
- Based on our reliability database, FIT datas can be provided if necessary.

PRODUCTION CONTROL

Test conducted on each lot according to ESCC-3009 for

FREQUENCY	TEST/STRESS	REFERENCE	AEC-Q	DETAIL
100%	Capa, DF, IR	CECC-32100-4.6		according to datasheet
100%	Visual	CECC-32100-4.5	AEC-Q200-9	no visual defects
50/lot	DPA		AEC-Q200-5	internal component integrity
5/lot	Dimension	CECC-32100-4.5	AEC-Q200-5	according to datasheet
5/lot	Resistance to soldering heat	CECC-32100-4.10	AEC-Q200-15	
5/lot	Solderability	CECC-32100-4.11	AEC-Q200-18	
10/lot	Voltage proof	CECC-32100-4.6.4		
1/ceramic lot	Temperature coefficient	CECC 32100-Prgph4,7		according to datasheet

QUALIFICATIONS

Each component family has been qualified according to CECC and AECQ tests methodology, which are renewed on a periodic basis.

FREQUENCY	TEST/STRESS	REFERENCE	AEC-Q	DETAIL
Qualif	Electrical Characterization	CECC-32100-4.6 4.7	AEC-Q200-19	measure before test according to datasheet and after test according to post environmental limits
Qualif	Temperature Cycling	JESD22 Method-JA method 104	AEC-Q200-4	1,000 cycles -55°C to +125°C Measurement at 24 ± 2 hours after test conclusion
Qualif	Biased Humidity	MIL-STD-202 Method 103	AEC-Q200-7	1,000 hours 85°C/85%RH. Rated voltage. Measurement at 24 ± 2 hours after test conclusion
Qualif	Operational Life	MIL-STD-202 Method 108 condition D	AEC-Q200-8	1,000 hours at 125°C with applied Voltage : 2xRV RV≤500V, 1.2xRV 500V<RV≤1250V, RV RV>1250V
Qualif	High Temperature Exposure (Storage)	MIL-STD-202 Method 108	AEC-Q200-3	1,000 hours at 150°C with 0V. Measurement at 24 ± 2 hours after test conclusion
Qualif	Terminal Strength	CECC-32100-4.8	AEC-Q200-6	1.8kg 60 seconds
Qualif	Vibration	MIL-STD-202 Method 204	AEC-Q200-14	5g 20min 12cycles 3 orientations 10-2000Hz
Qualif	Board Flex	CEC 32100-4.9	AEC-Q200-21	3mm Type 1, 2mm Type 2, Measurement at 24 ± 2 hours after test conclusion

POST ENVIRONMENTAL STRESS LIMIT

DIELECTRIC	DISSIPATION FACTOR (MAXIMUM)	CAPACITANCE SHIFT	INSULATION RESISTANCE
NPO	≤ 4 10 ⁻³	±2%	10% initial limit
N2T	≤ 6 10 ⁻³	±4%	10% initial limit
X7R	≤ 0.035	±15%	10% initial limit

SPACE LEVEL COMPONENT SCREENED AND QUALIFIED ACCORDING TO ESCC-3009

SRT-Microcéramique can propose a wide range of BME and PME component qualified and tested according to ESCC-3009 standard for space projects. Both for development en evaluation (D32) and flight ready with full lot validation and ESCC standard documentation. Specific qualification programmes can be included to meet final customer requirement.

PRODUCTION CONTROL/SCREENING

Tests conducted on each lot and screening for evaluation components D32 and flying components D30

FREQUENCY	TEST/STRESS	REFERENCE	DETAIL
Lot	DPA	ESCC-23400	Construction analysis
3/Lot	Dimension/weight	ESCC-20400/20500	Dimension in spec/max weight in spec
100%	Burn-In	ESCC-3009	168H, max T°, 2Ur Ur<500V, 1.5Ur Ur=500V, 1.3Ur 500V<Ur≤1250V, 1Ur Ur>1250V (fail<5%)
100%	Room Temperature Electrical Measurements	ESCC-3009	Cp, DF, IR, VP according to datasheet
5/lot	High and Low Temperatures Electrical Measurements	ESCC-3009	0 fail
100%	Visual Inspection	ESCC-20400/20500	

LOT VALIDATION

Lot validation for flying components D30

FREQUENCY	TEST/STRESS	REFERENCE	DETAIL
20/Lot	PCB Mounting, Rapid Change of Temperature, Steady State Humidity, external visual inspection	ESCC-3009/ IEC 60384-1/IEC 60068-2-14	
20/Lot	PCB Mounting, Life test	ECSS-3009/IEC 60384-1	1000H, max T°, 2Ur Ur<500V, 1.5Ur Ur=500V, 1.3Ur 500V<Ur≤1250V, 1Ur Ur>1250V
6/Lot	PCB Mounting, Temperature Characterisation, Robustness of Terminations	ESCC-3009/ IEC 60068-2-14/IEC 60384-1	
6/Lot	Solderability, Permanence of Marking	ECSS-3009/ IEC 60068-2-58/ ECSS-24800	

SPACE LEVEL COMPONENT SCREENED ACCORDING TO COTS+ ECSS-Q-ST-60-13C-REV1

SRT-Microcéramique can apply the COTS+ qualification framework to any suitable component AEQ-200 or not, to make them fly ready, offering a wide range of possibilities at competitive cost, either in Class 1 (COTS1), Class 2 (COTS2) or Class 3 (COTS3).

EVALUATION/SCREENING/LAT

Class 1 (COTS1), Class 2 (COTS2), Class 3 (COTS3)

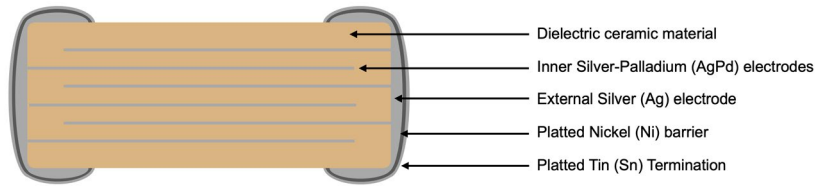
AECQ-200	CLASS 1	CLASS 2	CLASS 3	CATEGORY	TEST TYPE	SAMPLE	PROCEDURE
Yes	X	X	X	Evaluation	Construction Analysis	5	ESCC21001
Yes	X	X	X	Evaluation	Temperature characterization	5	ESCC3009 8.10
Yes	X			Evaluation	Life Test 2000h	40	ESCC3009 8.6 + 8.9
Yes	X			Screening	Complete screening	100%	ESCC3009 chart F3
Yes	X	X	X	LAT	DPA	3	ESCC21001
Yes	X	X		LAT	Life Test 1000h	20	ESCC3009 8.6 + 8.9
No	X	X	X	Evaluation	Construction Analysis	5	ESCC21001
No	X	X	X	Evaluation	Temperature characterization	5	ESCC 3009 8.10
No	X	X		Evaluation	Complete evaluation	72	ESCC 3009 chart F4
No			X	Evaluation	Life Test 1000h	40	ESCC3009 8.6 + 8.9
No	X	X	X	Screening	Complete screening	100%	ESCC3009 chart F3
No	X	X	X	LAT	DPA	3	ESCC21001
No	X			LAT	Complete LAT	52	ESCC 3009 chart F4
No		X	X	LAT	Life Test 1000h	20	ESCC3009 8.6 + 8.9

TINNING

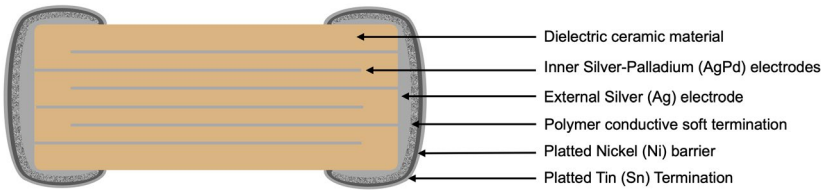
All component for space application can be proposed with dipped SnPb termination (Sn62 Pb36 Ag2) or SAC 305 (Sn96.5 Ag3 Cu0.5) for maximum reliability and whiskers avoidance.

This document is subject to change without notice.

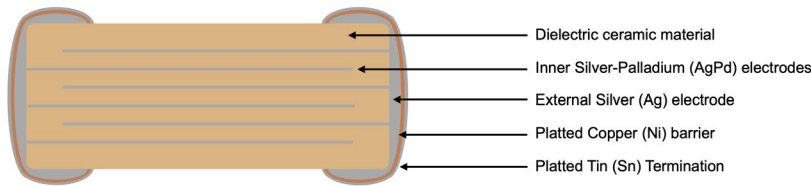
PME (Precious Metal Electrodes)



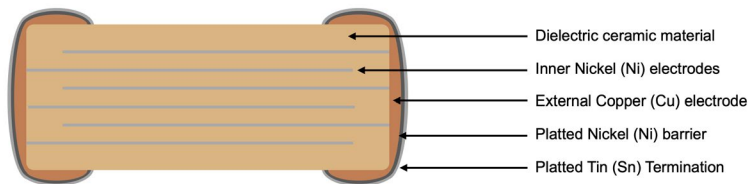
PME (Precious Metal Electrodes) Polymer Soft Termination



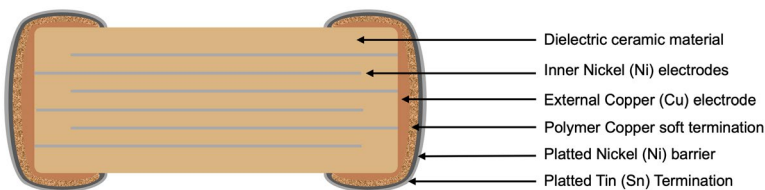
PME (Precious Metal Electrodes) Non Magnetic



BME (Basis Metal Electrodes) code BM



BME (Basis Metal Electrodes) code BM Polymer Soft Termination



REACH Compliance

- SRT-Microcéramique delivers non-chemical articles only.
- These contain no substances which are intended to be released under normal or reasonably foreseeable conditions of use according to Reach article 7(1).

SRT-Microcéramique confirms hereby that our products contain none of the substances which are listed in the present candidate list of the European Chemicals Agency (ECHA), above a concentration of 0.1% by weight of the whole component.

Candidate list of substances (European Chemicals Agency ECHA) :
<http://echa.europa.eu/fr/candidate-list-table>

ROHS COMPLIANCE

SRT-Microcéramique herewith confirms that RoHS-compliant SRT-microcéramique products are conforming to the following EU directives:
EU directive 2015/863/EU EU directive 2011/65/EU EU directive 2003/11/EC

Following restricted materials are not used and do not exceed the legal limits: Lead (Pb, see exemptions),

- Mercury (Hg)
- Cadmium (Cd)
- Chromium (Cr VI)
- Polybrominated biphenyls (PBB) Polybrominated diphenyl ethers (PBDE) Bis(2-Ethylhexyl) phthalate (DEHP) Benzyl butyl phthalate (BBP)
- Dibutyl phthalate (DBP) Diisobutyl phthalate (DIBP)

Exemptions: The following exemptions according to the RoHS annexe are applicable:

Identity 7(a) :

- Lead in high melting temperature type solders (i.e lead-based alloys containing 85% by weight or more lead).

Identity 7(c)-I :

- Electrical and electronic components containing lead in a glass or ceramic other than dielectric ceramic capacitors, e.g. piezoelectronic devices, or in a glass or ceramic matrix compound.

The components are suitable for a lead-free process according to EN 60068-2-58 and in accordance with the IPC/JEDEC standard J-Std-020D. The lead free process has been tested using solder alloy Sn96.5Ag3Cu0.5

Export controls and dual-use regulations

Some SRT-Microcéramique components fall under 'dual-use' items under international export controls definition - those that can be used for civil or military purposes which meet certain specified technical standards.

The defining criteria for a dual use component is one with a voltage rating of >750Vdc and a capacitance value of >250nF when measured at 750Vdc and a series inductance <10nH. Components defined as dual-use under the above criteria may require a licence for export across international borders. Please contact us for further information on specific part numbers.

ISO9001:2015

In their design, research and development as well as the manufacturing of MLCC capacitors, customer service and distribution SRT-Microcéramique uses and maintains a Management System audited and certified in accordance to : **ISO9001:2015**

You may contact us for any inquiry regarding the regulations and compliance listed above.